Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	5	wu-kang$.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:00
L3	222741	detect$3 near5 (fault$1 or error$1 or defect$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:11
L6	2232	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1)) near2 test$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:26
L9	924	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near2 test$4) and (vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:32
L11	42	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near2 test$4) and (product near3 vector$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:35
L12	72	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near5 test$4) and (optimal near2 test$3)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:36
L13	49	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near5 test$4) and (optimal near2 test$3) and vector$1	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:37
L14	6	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near5 test$4) and (select$3 near5 optimal near5 test$3) and vector$1	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:38
L15	6	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near5 test$4) and (select$4 near5 optimal near5 test$3) and vector$1	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:38

L16	1	(detect$3 near5 (fault$1 or error$1 or defect$1)) and ((IC or (integrated adj2 circuit$1) or chip$1 or dice$1) near5 test$4) and (select$4 near5 optimal near5 test$3) and (vector$1 near3 product$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/24 14:41

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